Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,160	CHIU, WEN-PIN
Examiner	Art Unit
Rodney G. McDonald	1753

SEARCHED					
Class	Subclass	Date	Examiner		
204	192.12	3/10/06	m		
204	192.17	<i>' j</i>			
201	192.15				
204	192.3	0/10/06	h		
204	298.06				
204	298.11	8/10/06	pu		
		/ /			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
<u>-</u>					
	į				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See EBST SEBREH	2/10/02	m		
•				
	:			
-				